

Sampling Run-to-Run Control of Mix-Product Semiconductor Processes
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Mechanical Engineering

Engineering

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Abstract

This paper developed a sampling run-to-run control technique for the mix-product semiconductor processes. The controller can individually estimate the disturbances caused by tools and products and keep the process outputs around the targets. Simulation results show that, for the mix-product processes with drifts and sampling-measurement, the performance of the proposed controller is superior to that of the independent D-EWMA controller.

Keyword : run-to-run control, mix-product, semiconductor processes, sampling-measurement